CONTRACT C REQUIREMENTS

PRON M131A376M1

AMC 1

AMSC G

ATC AWFDP

TDP 12549800

TDPL DATE 06/09/03

NSN 5998013083749 NOMENCLATURE CIRCUIT CARD ASSEMB

ENGINEERING EXCEPTIONS: The following engineering changes apply to this procurement action(s):

All drawings missing Distribution Statements will be assigned a "C" Distribution Statement for this procurement.

DOCUMENT	DELETE ADD
12549800	MIL-R-39008 MIL-PRF-39017
11 11	MIL-R-39008/1 MIL-PRF-39017/1
' II II	MIL-R-83726/13 MIL-PRF-83726/13
II II	MIL-S-13949 MIL-PRF-31032
11 11	MIL-S-13949/4 MIL-PRF-31032/4
12549801	MIL-STD-275 IPC-2221
п н	MIL-P-13949 MIL-PRF-31032
12549800	MIL-STD-45662 ISO-10012-1
12549800	FIND NO 42 MS16535-249 FIND NO MS16535-251 AND MS51859-4
12273301	FROM TO
	Change Address NATIONAL SEMICONDUCTOR
	2900 SEMICONDUCTOR DR.
	SANTA CLARA, CA. 95052-8090
	408-721-5000
	DISREGARD MOTOROLA AS A VENDOR FOR THIS PROCUREMENT.
	OBSOLETE PARTS ACCEPTABLE
12285991	Change 1st ADDRESS NATIONAL SEMICONDUCTOR
	2900 SEMICONDUCTOR DR.
	SANTA CLARA, CA. 95052
	DISREGARD SIGNETICS CORP. AS A VENDOR FOR THIS
*	PROCUREMENT, OBSOLETE PARTS ACCEPTABLE

12272076

FROM

NATIONAL SEMICONDUCTOR CORP

PO BOX 443

COMMERCE DRIVE

CANBUURY, CT. 06810

TO

NATIONAL SEMICONSUCTOR

2900 SEMICONDUCTOR

SANTA CLARA, CA 95052-8090

408-721-5000

12324449

CHANGE ADDRESS

MICROSEMI CORP.

11861 WESTERN AVE.

GARDEN GROVE, CA. 92641

714-898-8121

12347060

CHANGE 1ST ADDRESS

CYTEC INDUSTRIES INC. 1405 BUFFALO STREET

OLEAN, NY 14760

716-372-9650

PART NO. CE-1166 OBSOLETE

DISREGARD PRODUCTS RESEARCH AND CHEMICALS CORP AS A VENDOR

9376933

CHANGE ADDRESS

ONSEMICONDUCTOR 5005 MCDOWELL RD

PHOENIX , ARIZONA 85008

800-282-9800

PART NO.1N5822 VERIFIED GOOD

Document Add Distribution Statement "C" SPEC ATPD-2167, S-001 " " SPEC SA-X00003D, S-001 " "

SC-X16454C S-001, Add Distribution Statement "C"

SC-X16454C S-002, STANDARDS, Military - MIL-STD-105 Replace with MIL-STD-1916.

SC-X16454C S-015, 4.1.3 Quality Conformance Conditions and Controls. - Delete "as indicated by the existence of an Acceptable Quality Level (AQL) or frequency of inspection number in one of the classification characteristics columns."

Delete NOTE 2.

SC-X16454C S-015, 4.1.3.1.1 Sampling - Delete Paragraph. - Replace with "Sampling and inspection shall be conducted in accordance with MIL-STD-1916".

SC-X16454C S-015, 4.1.3.1.1.1 AQL Validation. - Delete Paragraph.

SC-X16454C S-015, 4.1.3.1.1.2 Sampling Failures. - Delete Paragraph.